

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKAHARA ET AL.	
		Examiner Thomas L Dickey	Art Unit 2826	Page 1 of 1

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*	C	US-2002/0131466	09-2002	Salvatore et al.	372/50
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.